

G. E. VAN WERT CO INC. 461 BOSTON ST. TOPSFIELD, MA. 01983 (978) 887-3389 E-MAIL: ERICP@GEVANWERT.COM

VAN WERT Wafer Thickness Gage



ACCURACY: .00002" (.5 MICRON)
RESOLUTION: .000004" (.0001MICRON)
PROBE TRAVEL: .500" OR 1.0000" (12MM OR 25MM)
MAXIMUM PART SIZE: 12"X 4" (300MM X 100MM)

THE VAN WERT PRECISION THICKNESS GAGE IS THE PERFECT GAGE FOR SEMICONDUCTOR WAFERS, OPTICS AND MANY OTHER HIGH ACCURACY THICKNESS AND FLATNESS MEASUREMENTS. THE VAN WERT GAGE UTILIZES TWO OPPOSING HEIDENHAIN DIGITAL LENGTH PROBES WHICH ARE PNEUMATICALLY ACTIVATED FOR SMOOTH DELICATE TOUCH OPERATION. THE GAGE EMPLOYS A DIFFERENTIAL MEASURING TECHNIQUE WHICH ELIMINATES THE ERROR IN THICKNESS MEASURING INTRODUCED BY THE FLATNESS DEVIATION BETWEEN THE WORK PIECE AND THE GRANITE REFERENCE SURFACE, ELIMINATING BOW AND AIR POCKETS PROBLEMS. THE "GAGE CHEK" DIGITAL DISPLAY CAN DISPLAY THE ACTUAL PROBE READING. THE DISPLAY CAN ALSO COLLECT AND PRINT DATA AND STORE MULTIPLE PART SETUPS. PLEASE CALL FOR A DEMONSTRATION OR A FORMAL QUOTATION